

Principles of Data Conversion System Design

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Contents

PREFACE *xi*

**CHAPTER 1 INTRODUCTION TO DATA CONVERSION
AND PROCESSING** **1**

CHAPTER 2 BASIC SAMPLING CIRCUITS **7**

2.1 General Considerations **7**

2.2 Performance Metrics **11**

2.3 Sampling Switches **13**

2.3.1 MOS Switches **14**

2.3.2 Diode Switches **19**

2.3.3 Comparison of MOS and Diode Switches **23**

2.3.4 Improvements in MOS Switch Performance **24**

References **27**

CHAPTER 3 SAMPLE-AND-HOLD ARCHITECTURES **29**

3.1 Conventional Open-Loop Architecture **29**

3.2 Conventional Closed-Loop Architecture **31**

3.3 Open-Loop Architecture with Miller Capacitance **33**

- 3.4 Multiplexed-Input Architectures 35
- 3.5 Recycling Architecture 39
- 3.6 Switched-Capacitor Architecture 40
- 3.7 Current-Mode Architecture 42
- References 43

CHAPTER 4 BASIC PRINCIPLES OF DIGITAL-TO-ANALOG CONVERSION 45

- 4.1 General Considerations 45
- 4.2 Performance Metrics 47
- 4.3 Reference Multiplication and Division 49
 - 4.3.1 Voltage Division 50
 - 4.3.2 Current Division 55
 - 4.3.3 Charge Division 63
- 4.4 Switching and Logical Functions in DACs 70
 - 4.4.1 Switching Functions in Resistor-Ladder DACs 70
 - 4.4.2 Switching Functions in Current-Steering DACs 72
 - 4.4.3 Switching Functions in Capacitor DACs 74
 - 4.4.4 Binary-to-Thermometer Code Conversion 76
- References 77

CHAPTER 5 DIGITAL-TO-ANALOG CONVERTER ARCHITECTURES 79

- 5.1 Resistor-Ladder DAC Architectures 79
 - 5.1.1 Ladder Architecture with Switched Subdivider 79
 - 5.1.2 Intermeshed Ladder Architectures 82
- 5.2 Current-Steering Architectures 84
 - 5.2.1 R - $2R$ -Network Based Architectures 84
 - 5.2.2 Segmented Architectures 90
- References 94

CHAPTER 6 ANALOG-TO-DIGITAL CONVERTER ARCHITECTURES 96

- 6.1 General Considerations 96
- 6.2 Performance Metrics 99
- 6.3 Flash Architectures 101
 - 6.3.1 Reference Ladder DC and AC Bowing 103
 - 6.3.2 Nonlinear Input Capacitance 106

- 6.3.3 Kickback Noise 107
- 6.3.4 Sparkles in Thermometer Code 108
- 6.3.5 Metastability 110
- 6.3.6 Slew-Dependent Sampling Point 112
- 6.3.7 Clock Jitter and Dispersion 112
- 6.3.8 Gray Encoding 114
- 6.4 Two-Step Architectures 116
 - 6.4.1 Effect of Nonidealities 121
 - 6.4.2 Two-Step Recycling Architecture 124
 - 6.4.3 Two-Step Subranging Architecture 125
- 6.5 Interpolative and Folding Architectures 126
 - 6.5.1 Interpolation 127
 - 6.5.2 Folding Architectures 132
 - 6.5.3 Folding with Interpolation 136
- 6.6 Pipelined Architectures 140
- 6.7 Successive Approximation Architectures 143
- 6.8 Interleaved Architectures 147
- References 149

CHAPTER 7 BUILDING BLOCKS OF DATA CONVERSION SYSTEMS 153

- 7.1 Amplifiers 153
 - 7.1.1 Open-Loop Amplifiers 153
 - 7.1.2 Closed-Loop Amplifiers 160
 - 7.1.3 Operational Amplifiers 164
 - 7.1.4 Gain Boosting Techniques 171
 - 7.1.5 Common-Mode Feedback 172
- 7.2 Comparators 177
 - 7.2.1 Bipolar Comparators 181
 - 7.2.2 CMOS Comparators 188
 - 7.2.3 BiCMOS Comparators 191
- References 195

CHAPTER 8 PRECISION TECHNIQUES 198

- 8.1 Comparator Offset Cancellation 198
 - 8.1.1 Input Offset Storage 199
 - 8.1.2 Output Offset Storage 201
 - 8.1.3 Multistage Offset Storage 202
 - 8.1.4 Comparators Using Offset-Cancelled Latches 206
- 8.2 Op Amp Offset Cancellation 208

8.3	Calibration Techniques	211
8.3.1	DAC Calibration Techniques	211
8.3.2	ADC Calibration Techniques	218
8.4	Range Overlap and Digital Correction	224
	References	229

CHAPTER 9 TESTING AND CHARACTERIZATION 232

9.1	General Considerations	232
9.2	Sampling Circuits	234
9.3	D/A Converters	239
9.4	A/D Converters	239
9.4.1	Static Testing	239
9.4.2	Dynamic Testing	241

INDEX 252